

PointProbe® Plus Non-Contact / Soft Tapping Mode - Reflex Coating

The PointProbe® Plus (PPP) combines high application versatility and compatibility with most commercial SPMs. The typical AFM tip radius of less than 7 nm and the minimized variation in AFM tip shape provide reproducible images and enhanced resolution.

NANOSENSORS™ PPP-NCSTR AFM probes are designed for non-contact or soft tapping mode imaging. The combination of soft AFM cantilever and fairly high resonance frequency enables stable and fast measurements with reduced AFM tip-sample interaction. This feature significantly reduces AFM tip wear and sample wear at the same time.

The AFM probe offers unique features:

- guaranteed AFM tip radius of curvature < 10 nm
- AFM tip height 10 - 15 µm
- highly doped silicon to dissipate static charge
- Al coating on detector side of AFM cantilever
- chemically inert
- high mechanical Q-factor for high sensitivity

This AFM probe features alignment grooves on the back side of the holder chip. These grooves fit to the NANOSENSORS Alignment Chip.

Cantilever data:

Property	Nominal Value	Specified Range
Resonance Frequency [kHz]	160	75 - 265
Force Constant [N/m]	7.4	1.2 - 29
Length [µm]	150	140 - 160
Mean Width [µm]	27	19.5 - 34.5
Thickness [µm]	2.8	1.8 - 3.8

Order codes and shipping units:

Order Code	AFM probes per pack	Data sheet
PPP-NCSTR-10	10	of all probes
PPP-NCSTR-20	20	of all probes
PPP-NCSTR-50	50
PPP-NCSTR-W	380	of up to 32 probes